IN THE CLAIMS

This listing of claims replaces all prior versions and listings of the claims in the abovereferenced application.

- 1. (Previously Presented) A structure comprising:
 - a semiconductor light emitting device; and
- a substrate comprising a ceramic core and at least one copper layer overlying the core, the at least one copper layer having a thickness of at least 4 mils;

wherein the semiconductor light emitting device is electrically connected to the at least one copper layer and wherein the substrate is configured to have a thermal conductivity of at least 24 W/m·K.

- 2. (Original) The structure of claim 1 wherein the semiconductor light emitting device comprises a III-nitride light emitting layer.
- 3. (Previously Presented) The structure of claim 1 wherein the core comprises a material selected from the group of Al₂O₃, AlN, alumina, and silicon nitride.
- 4. (Currently Amended) The structure of claim 1 further comprising at least one lead directly connected to the substrate.
- 5. (Previously Presented) The structure of claim 1 further comprising at least one solder pad connected to the substrate.
- 6. (Previously Presented) The structure of claim 1 further comprising at least one terminated wire connected to the substrate.
- 7. (Previously Presented) The structure of claim 1 wherein a bond disposed between the at least one copper layer and the core is a direct copper bond.
- 8. (Previously Presented) The structure of claim 1 wherein a bond disposed between the at least one copper layer and the core is an active metal braze.
- 9. (Previously Presented) The structure of claim 1 wherein the at least one copper layer

-2-

PATENT LAW GROUP LLP 2635 N. FIRST ST. SUITE 223 SAN JOSE, CA 95134 (408) 382-0480 FAX (408) 382-0481 has a thickness between 4 mils and about 24 mils.

- 10. (Original) The structure of claim 1 wherein the substrate is a first substrate, the structure further comprising a second substrate disposed between the semiconductor light emitting device and the first substrate.
- 11. (Original) The structure of claim 10 wherein the second substrate comprises at least one metal bonding pad and an insulating layer.
- 12. (Previously Presented) The structure of claim 11 wherein the insulating layer comprises one of AlN, Al₂O₃, and silicon nitride.
- 13. (Original) The structure of claim 10 wherein the second substrate comprises a silicon integrated circuit.
- 14. (Original) The structure of claim 1 further comprising a base connected to the substrate.
- 15. (Original) The structure of claim 1 further comprising a lens disposed over the semiconductor light emitting device.
- 16. (Previously Presented) The structure of claim 1 wherein the at least one copper layer is bonded to the core.
- 17. (Previously Presented) The structure of claim 1 wherein the at least one copper layer is bonded to the core by a process comprising:

forming an oxide coating on a sheet of copper; placing the oxide coating adjacent to the core; and heating the oxide coating to form a eutectic melt.

18-23. (Canceled)

24. (Previously Presented) The structure of claim 1 wherein the at least one copper layer is in direct contact with the ceramic core.

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- 25. (Previously Presented) The structure of claim 1 wherein the semiconductor light emitting device is configured to operate at a current density of at least 50 A/cm².
- 26. (Previously Presented) The structure of claim 1 wherein the semiconductor light emitting device is configured to operate at an electrical power consumption of at least 1 W.
- 27. (Previously Presented) The structure of claim 1 wherein the substrate is configured to operate at a temperature up to 800° C.

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